

SK40MLLE120CR03TE1



SEMITOP®E1

Double Boost + Bypass (Full SiC)

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Features*

- Optimized design for superior thermal performance
- Extremely low inductance design
- Press-Fit contact technology
- 1200V Planar Gen3 SiC MOS
- Simple to drive with +15V gate voltage
- SiC Schottky diode
- New PEP diode technology for enhanced power and environmental robustness
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

Typical Applications

- Solar

Remarks

- Recommended $T_{j,op} = -40 \dots +150 \text{ °C}$
- Recommended turn-off / turn-on gate voltage $V_{GS} = -4 \dots 0 / +15 \text{ V}$
- Diode1: Bypass and Protection Diodes D1 & D3
- Diode2: Boost SiC Diode D2

Absolute Maximum Ratings

Symbol	Conditions		Values	Unit
MOSFET 1				
V _{DSS}			1200	V
I _D	T _j = 175 °C	T _s = 25 °C	51	A
		T _s = 70 °C	43	A
I _{DM}	t _p limited by T _{vjmax}		120	A
V _{GS}	Transient Gate - Source voltage (t < 100ns)		-8 ... 19	V
T _j			-40 ... 175	°C
Integrated body diode				
I _{SM}	t _p limited by T _{vjmax}		120	A
I _{FSM}	t _p = 10 ms, sin 180°, T _i = 150°C		220	A

Absolute Maximum Ratings

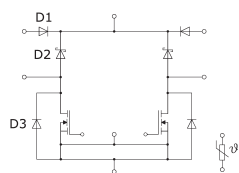
Symbol	Conditions		Values	Unit
Diode 1				
V _{RRM}	T _j = 25 °C		1200	V
I _F	T _j = 175 °C	T _s = 25 °C	69	A
		T _s = 70 °C	55	A
I _{FSM}	10 ms, sin 180°, T _j = 150 °C		270	A
i ² t	10 ms, sin 180°, T _j = 150 °C		364	A ² s
T _j			-40 ... 175	°C

Absolute Maximum Ratings

Symbol	Conditions		Values	Unit
Diode 2				
V _{RRM}	T _j = 25 °C		1200	V
I _F	T _j = 175 °C	T _s = 25 °C	37	A
		T _s = 70 °C	30	A
I _{FRM}			40	A
I _{FSM}	8.3 ms	T _j = 25 °C	80	A
	sin 180°	T _j = 150 °C	62	A
T _j			-40 ... 175	°C

Absolute Maximum Ratings

Symbol	Conditions	Values	Unit
Module			
$I_{t(RMS)}$	$\Delta T_{terminal}$ at PCB joint = 30 K, per pin	30	A
T_{stg}	module without TIM	-40 ... 125	°C
V_{isol}	AC, sinusoidal, $t = 1 \text{ min}$	2500	V



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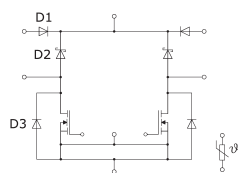
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Remarks

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Characteristics					
Symbol	Conditions	min.	typ.	max.	Unit
MOSFET 1					
$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 11.5 \text{ mA}, T_j = 25 \text{ }^{\circ}\text{C}$	1.8	2.5	3.6	V
I_{DSS}	$V_{GS} = 0 \text{ V}, V_{DS} = 1200 \text{ V}, T_j = 25 \text{ }^{\circ}\text{C}$			0.2	mA
I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = 15 \text{ V}, T_j = 25 \text{ }^{\circ}\text{C}$			400	nA
$R_{DS(on)}$	$V_{GS} = 15 \text{ V}$ $I_D = 41 \text{ A}$ chiplevel		$T_j = 25 \text{ }^{\circ}\text{C}$ $T_j = 150 \text{ }^{\circ}\text{C}$	32 43	mΩ
C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 1000 \text{ V}, f = 0.1 \text{ MHz}$		3400		pF
C_{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 1000 \text{ V}, f = 0.1 \text{ MHz}$		130		pF
C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 1000 \text{ V}, f = 0.1 \text{ MHz}$		10		pF
R_{Gint}	$T_j = 25 \text{ }^{\circ}\text{C}$		1.7		Ω
Q_G	$V_{DD} = 800 \text{ V}, V_{GS} = -4 \text{ V} \dots 15 \text{ V}, I_D = 41 \text{ A}$		118		nC
$t_{d(on)}$	$V_{DD} = 600 \text{ V}$ $V_{GS} = 15 / -4 \text{ V}$ $I_D = 40 \text{ A}$		$T_j = 150 \text{ }^{\circ}\text{C}$	33	ns
$t_{d(off)}$			$T_j = 150 \text{ }^{\circ}\text{C}$	76	ns
t_r	$R_{Gon} = 9.1 \text{ } \Omega$		$T_j = 150 \text{ }^{\circ}\text{C}$	16	ns
t_f	$R_{Goff} = 9.1 \text{ } \Omega$		$T_j = 150 \text{ }^{\circ}\text{C}$	16	ns
E_{on}	$di/dt_{off} = 2.9 \text{ kA}/\mu\text{s}$ $di/dt_{on} = 2.7 \text{ kA}/\mu\text{s}$		$T_j = 150 \text{ }^{\circ}\text{C}$	0.28	mJ
E_{off}	$dv/dt = 67 \text{ kV}/\mu\text{s}$		$T_j = 150 \text{ }^{\circ}\text{C}$	0.28	mJ
$R_{th(j-s)}$	per MOSFET, HPTP / HP-PCM		0.92		K/W
Integrated body diode					
$V_F = V_{SD}$	$-I_D = 21 \text{ A}$ $V_{GS} = -4 \text{ V}$ chiplevel		$T_j = 25 \text{ }^{\circ}\text{C}$ $T_j = 150 \text{ }^{\circ}\text{C}$	4.62 4.31	V
$V_{F0} = V_{SD0}$	chiplevel		$T_j = 25 \text{ }^{\circ}\text{C}$ $T_j = 150 \text{ }^{\circ}\text{C}$	3.80 3.60	V
$r_F = r_{SD}$	chiplevel		$T_j = 25 \text{ }^{\circ}\text{C}$ $T_j = 150 \text{ }^{\circ}\text{C}$	39 34	mΩ
t_{rr}	$V_{DD} = 600 \text{ V}$ $-I_D = 40 \text{ A}$		$T_j = 150 \text{ }^{\circ}\text{C}$	-	ns
Q_{rr}	$V_{GS} = -4 \text{ V}$		$T_j = 150 \text{ }^{\circ}\text{C}$	-	μC
I_{rr}			$T_j = 150 \text{ }^{\circ}\text{C}$	-	A
E_{rr}	$di/dt_{off} = 2.9 \text{ kA}/\mu\text{s}$		$T_j = 150 \text{ }^{\circ}\text{C}$	-	mJ

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Diode 1						
V _F	I _F = 20 A	T _j = 25 °C		1.01	1.26	V
	chiplevel	T _j = 150 °C		0.91	1.15	V
V _{F0}		T _j = 25 °C		0.89	1.09	V
	chiplevel	T _j = 150 °C		0.73	0.92	V
r _F		T _j = 25 °C		6.2	8.5	mΩ
	chiplevel	T _j = 150 °C		8.8	12	mΩ
I _R		T _j = 150 °C, V _{RRM}			2	mA
R _{th(j-s)}	per Diode, HPTP / HP-PCM			1.21		K/W



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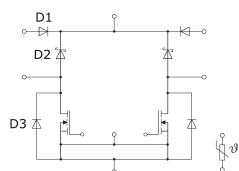
Remarks

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- Recommended turn-off / turn-on gate voltage $V_{GS} = -4 \dots 0/+15\text{V}$
- Diode1: Bypass and Protection Diodes D1 & D3
- Diode2: Boost SiC Diode D2

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Diode 2						
V _F	I _F = 20 A	T _j = 25 °C		1.40	1.60	V
	chipelevel	T _j = 150 °C		1.80	2.10	V
V _{F0}	chipelevel	T _j = 25 °C		0.95	1.05	V
		T _j = 150 °C		0.83	0.90	V
r _F	chipelevel	T _j = 25 °C		23	28	mΩ
		T _j = 150 °C		49	60	mΩ
C _j	V _R = 800 V, f = 1 MHz, T _j = 25 °C			0.085		nF
Q _c	V _R = 800 V, di/dt _{off} = 500 A/μs, T _j = 25 °C			0.066		μC
R _{th(j-s)}	per Diode, HPTP / HP-PCM			1.19		K/W

Characteristics					
Symbol	Conditions	min.	typ.	max.	Unit
Module					
L _{CE}		10			nH
M _s	to heatsink	1.6		2.3	Nm
w	weight	25			g

Characteristics					
Symbol	Conditions	min.	typ.	max.	Unit
Temperature Sensor					
R ₁₀₀	T _c =100°C (R ₂₅ =5 kΩ)	493 ± 5%			Ω
B _{100/125}	R _(T) =R ₁₀₀ exp[B _{100/125} (1/T-1/T ₁₀₀)]; T[K];	3550 ±2%			K



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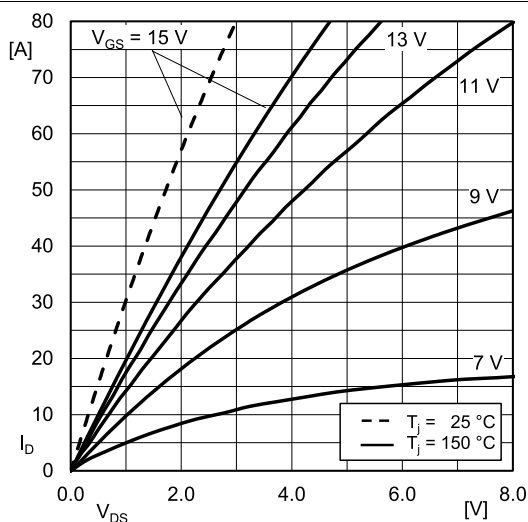


Fig. 1: Typ. MOSFET forward output characteristic, incl. $R_{DS(on)} + SS$

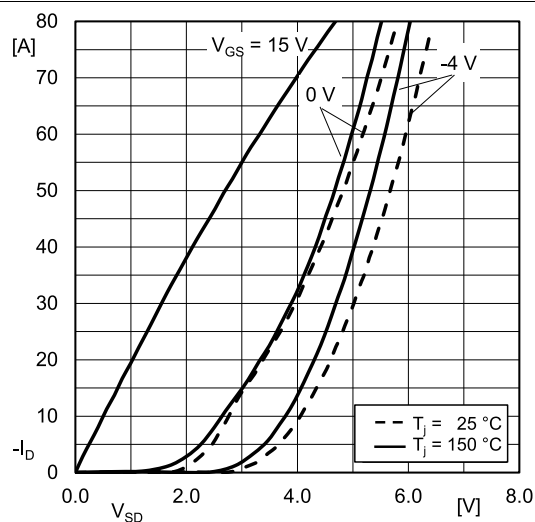


Fig. 1a: Typ. MOSFET reverse output characteristics, incl. $R_{DS(on)} + SS$

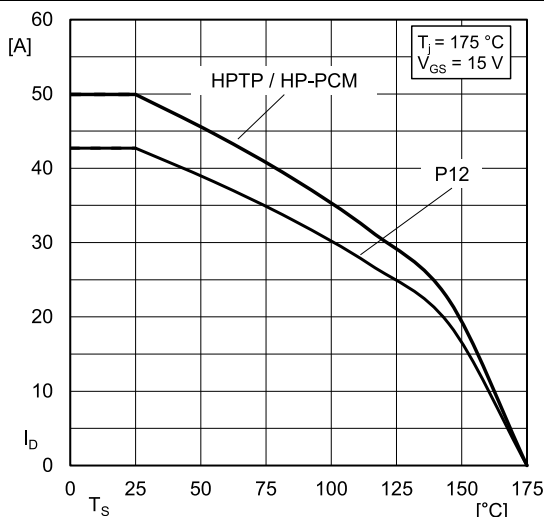


Fig. 2: MOSFET Rated current vs. Temperature $I_c = f(T_s)$

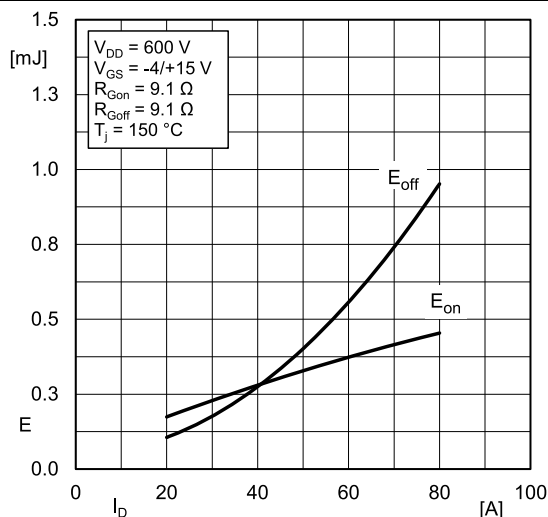


Fig. 3: Typ. MOSFET switching energy $E = f(I_D)$

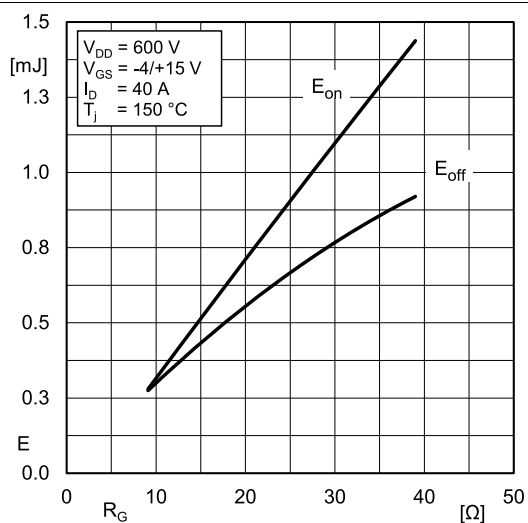


Fig. 4a: Typ. MOSFET switching energy $E = f(R_G)$

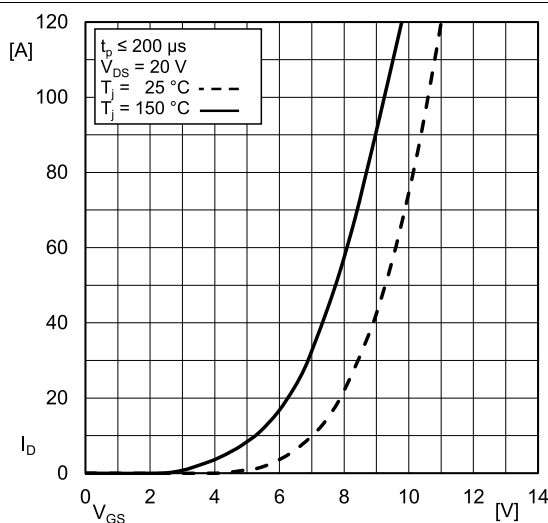


Fig. 5: Typ. MOSFET transfer characteristic

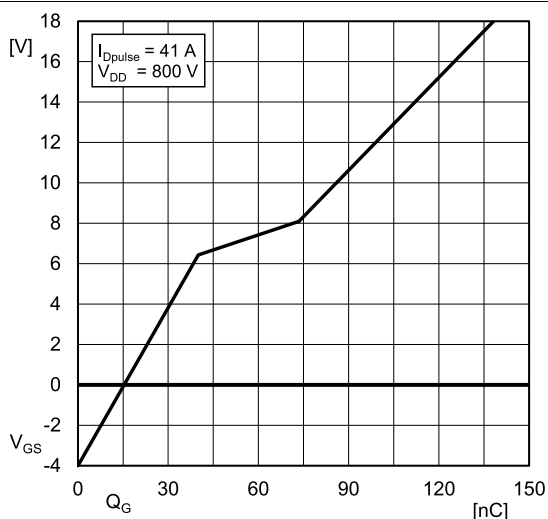


Fig. 6: Typ. MOSFET gate charge characteristic

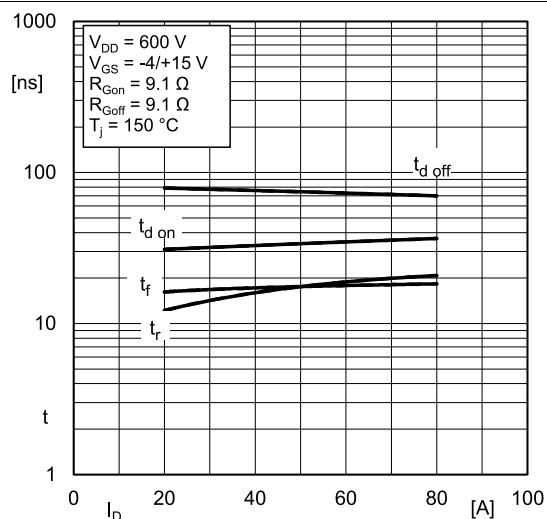


Fig. 7: Typ. MOSFET switching times $t = f(I_D)$

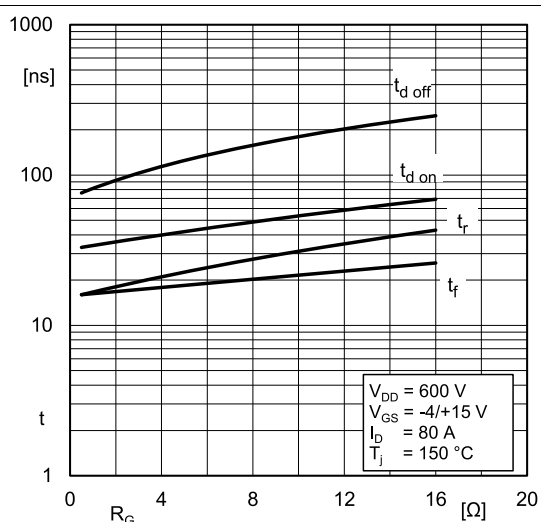


Fig. 8: Typ. MOSFET switching times $t = f(R_G)$

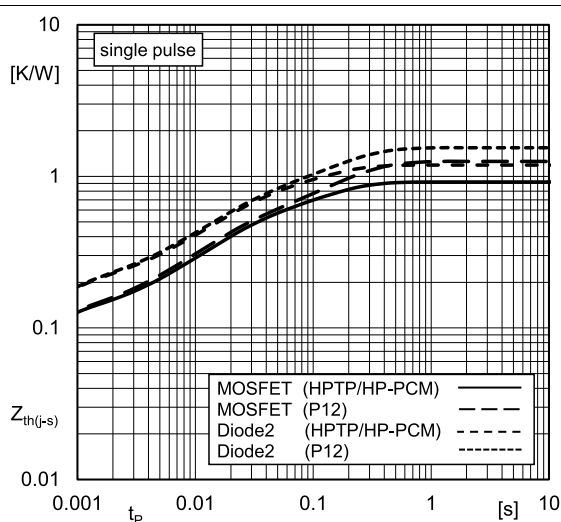


Fig. 9: Typ. transient thermal impedance

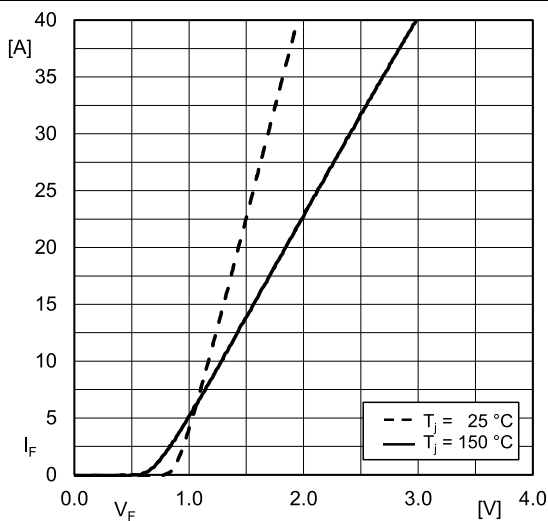


Fig. 10: Typ. Diode2 forward characteristic, incl. $R_{CC+EE'}$

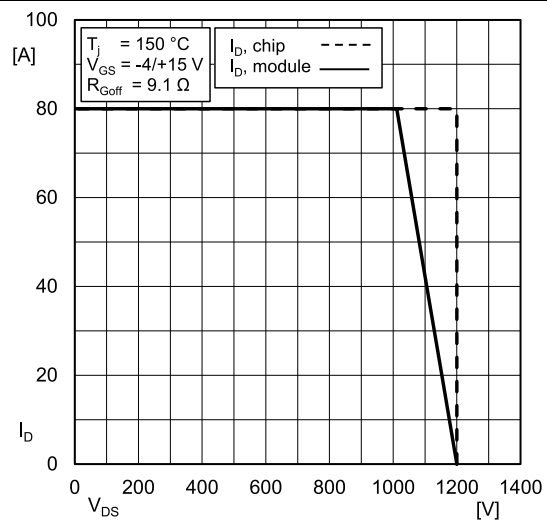


Fig. 13: MOSFET Reverse Bias Safe Operating Area (RBSOA)

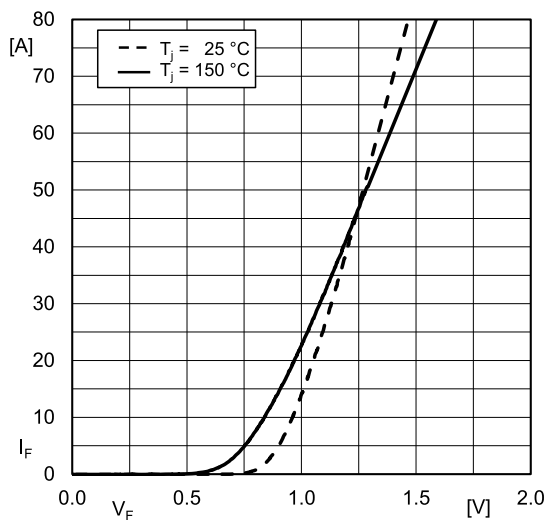
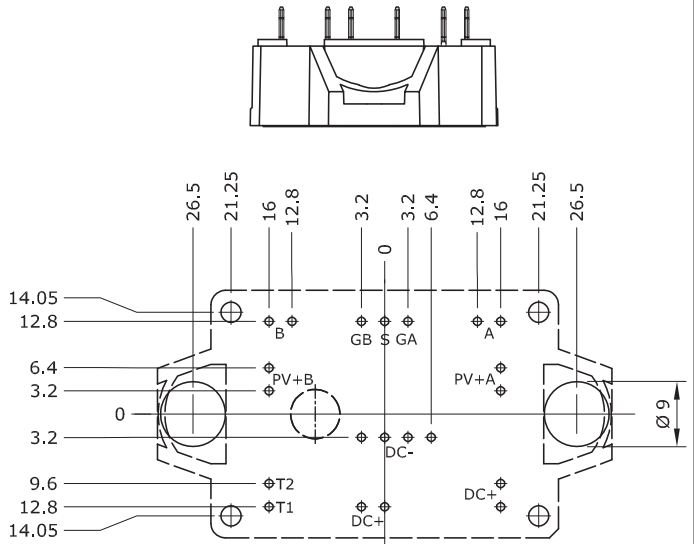
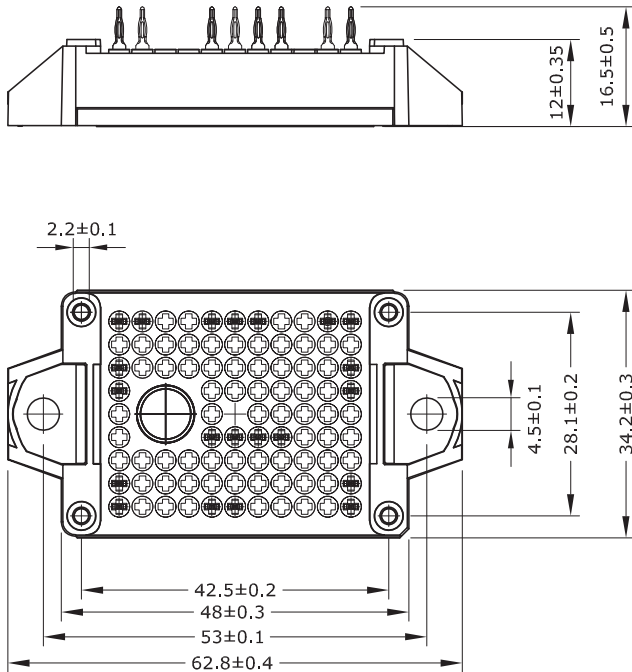


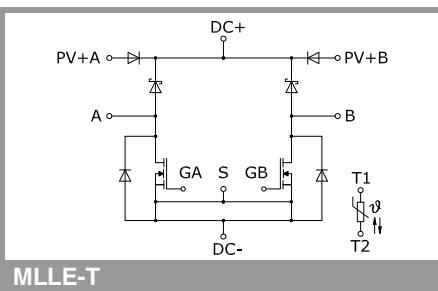
Fig. 14: Typ. Diode1 forward characteristic, incl. $R_{CC'+EE'}$

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- Pin-Grid 3.2 mm
- Tolerance of PCB hole pattern $\boxed{\Phi 0.1}$
- Diameters of drill $\Phi 1.15\text{mm}$
- Copper thickness in hole 25 - 50 μm
- Hole specification for contacts:
refer to SEMITOP E1/E2 Mounting Instruction

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IMPORTANT INFORMATION AND WARNINGS

This is an electrostatic discharge sensitive device (ESDS) according to international standard IEC 61340.

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